

VIA EFS

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In Re Patent Application: Luca Pusterla, et al. §  
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Conf. No.: 7623 § Group Art Unit: 1743  
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Appln. No.: 10/601,383 § Examiner: Yelena G. Gakh  
§  
Filing Date: June 23, 2003 § Atty. Docket No.: 6023-169US  
§ (BX2453M)  
Title: METHOD FOR MEASURING THE CONCENTRATION OF IMPURITIES IN  
HELIUM BY ION MOBILITY SPECTROMETRY

**RESPONSE TO ELECTION OF SPECIES REQUIREMENT**

This is in response to the Office Action (Election of Species requirement) dated August 22, 2006 (Paper No. 20060817). This response is being timely submitted by September 22, 2006.